Themed Issue on

Advances in Metrology and Quality Engineering

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edp sciences

Background

Metrology and quality engineering have always been playing a fundamental role in the development of all industries and societies. The effective and efficient solutions to many important problems currently facing the world call for the continual advances of the science and technology in the field of metrology and quality engineering.

Aim and Scope of the Themed Issue

The aim of this special issue is to present some of the latest progresses in metrology and quality engineering. It will cover the development of new metrology and quality standards, uncertainty evaluation, advanced product design, process control and optimization, predicative maintenance, sensors and instrumentation, advanced measurement systems, IoT, advanced data analytics, knowledge based systems, digital twins, robotics, machine learning and AI for applications in various industries, particularly in Industry 4.0 oriented advanced manufacturing, aerospace, energy, construction and healthcare.

Submissions

All relevant papers will be carefully considered, reviewed by a distinguished team of international experts, and published in accordance to the Journal's standard policies. Full research and review articles can be submitted online via the journal's submission and peer review site**.** Please register choosing the title of the special issue ***'Advances in Metrology and Quality Engineering'*****.**

Please find the instructions for authors at:
https://www.metrology-journal.org/author-information/instructions-for-authors

Submission deadline – 30th November 2020

Article submission and editorial system **here**.

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